

US Patent & Trademark Office

Patent Public Search | Text View

United States Patent Application Publication

20250266911

Kind Code

A1

Publication Date

August 21, 2025

Inventor(s)

Kumar; Rapina Siva et al.

SYSTEM AND METHODS FOR OFFSET AND THRESHOLD CALIBRATION IN LOSS OF SIGNAL DETECTION CIRCUITS

Abstract

Communication circuits and systems may include circuitry to detect the loss of the input signal. These circuits may be termed Loss of Signal (LOS) circuits. Changes to channel length and frequency of transmission may introduce uncertainty in detection circuits. A system may include a offset calibration mode and a hysteresis calibration mode to modify circuit performance in the presence of variations in process, voltage and temperature (PVT) and may improve performance of LOS circuits.

Inventors: Kumar; Rapina Siva (Bengaluru, IN), Jain; Shashi (Bengaluru, IN)

Applicant: Microchip Technology Incorporated (Chandler, AZ)

Family ID: 1000008099055

Assignee: Microchip Technology Incorporated (Chandler, AZ)

Appl. No.: 18/800049

Filed: August 10, 2024

Foreign Application Priority Data

IN 202411011021

Feb. 16, 2024

Publication Classification

Int. Cl.: H04B17/21 (20150101); H03K5/24 (20060101); H04L27/00 (20060101)

U.S. Cl.:

CPC H04B17/21 (20150115); H03K5/24 (20130101); H04L27/0002 (20130101)

Background/Summary

PRIORITY

[0001] This application claims priority to commonly owned Indian Provisional Patent Application No. 202411011021 filed Feb. 16, 2024, the entire contents of which are hereby incorporated by reference for all purposes.

FIELD OF THE INVENTION

[0002] The present disclosure relates to a system and method for calibrating offsets and thresholds in loss of signal detection circuit.

BACKGROUND

[0003] Communication circuits and systems may include circuitry to detect the loss of the input signal. These circuits may be termed Loss of Signal (LOS) circuits.

[0004] An LOS circuit may include an envelope detector which checks whether the input signal has enough amplitude or not to be reconstructed by the analog front-end (AFE). If the input signal has amplitude lower than a minimum threshold, the LOS circuit may output a signal in a first polarity to indicate detection of a loss of the input signal. If the input signal has amplitude higher than a minimum threshold, then the LOS circuit may output a signal in a second polarity to indicate presence of the input signal.

[0005] LOS circuits must work for all communication speeds and for all possible data types, modulation formats and channel configurations supported by the device. These and other constraints may require a wide bandwidth of operation in the LOS circuit.

[0006] LOS circuits must also operate across a wide range of possible channel lengths. As data rate changes the maximum channel length changes proportionally and this may lead to more uncertainty.

[0007] The LOS circuit detection threshold should be calibrated to the middle of the range to get the optimum performance. Apart from signal random pattern, process, voltage and temperature (PVT) variations also change the threshold of the LOS circuit.

[0008] To compensate the spread of input signal amplitudes which LOS detects, run length and PVT Programmability and Calibration of the LOS Threshold is needed. In addition, offset compensation is proposed to improve the LOS performance further.

[0009] There is a need for circuitry which may calibrate the offsets and thresholds in an LOS circuit to compensate for variations due to PVT, run length and data rates.

SUMMARY

[0010] The examples herein enable a system for calibration of offset and hysteresis in a communication system.

[0011] According to one aspect, a system includes one or more signal inputs coupled to a first switch network and coupled to an analog front end (AFE) circuit. A comparator may include one or more comparator inputs, a hysteresis control code input and at least one offset voltage input. The first switch network may selectively couple one of the one or more signal inputs and one or more calibration voltage inputs to the one or more comparator inputs. The comparator may be coupled to a calibration control circuit. A transition detection circuit may be coupled to one or more outputs of the comparator and the transition detection circuit may generate a signal detection indicator. The calibration control circuit may include a programmable divider to divide a reference clock. The calibration control circuit may include a variable amplitude signal generator to receive the output of the programmable divider and an amplitude control code. The variable amplitude signal generator may generate a signal with an amplitude based on the amplitude control code. A second switch network may receive input from the output of the variable amplitude signal generator and from a common mode voltage. The second switch network may couple the common mode voltage to the

calibration voltage inputs in an offset calibration mode and the second switch network may couple the outputs of the variable amplitude signal generator to the calibration voltage inputs in a hysteresis calibration mode. A threshold calibration circuit may take input from the signal detection indicator and may generate a hysteresis control signal. The hysteresis control signal may be coupled to the hysteresis control code input of the comparator. The threshold calibration circuit may generate the amplitude control signal and the amplitude control signal may be coupled to the variable amplitude signal generator. An offset calibration logic circuit may take input from the one or more outputs of the comparator and may generate the at least one offset voltage input to the comparator. A controller may receive input from the comparator output and the signal detection indicator and may enable the offset calibration mode and the hysteresis calibration mode based on the comparator output and the signal detection indicator.

[0012] According to one aspect, a method may include steps of: performing an offset calibration of a comparator, the offset calibration comprising steps of: coupling one or more inputs of a comparator to a common mode voltage, setting a hysteresis control code, coupling the hysteresis control code to a hysteresis setting input of the comparator, sweeping an offset control code to the comparator in one or more steps from a first value to a second value, detecting a change in polarity of the comparator output, recording a value of the offset control code corresponding to the change in polarity of the comparator output for respective values of the hysteresis control code, and repeating the offset calibration for respective values of the hysteresis control code to generate a first look-up table of offset control codes and respective hysteresis control codes. The method may include steps of: performing a hysteresis calibration of the comparator, the hysteresis calibration comprising: setting an amplitude control code and a hysteresis control code, coupling the amplitude control code to an input of a variable amplitude signal generator and coupling the hysteresis control code to the comparator, sweeping the hysteresis control code in one or more steps from a minimum value to a maximum value and setting the offset voltage input to the comparator at respective steps based on values recorded in the first look-up table, detecting a signal detection indicator of a transition detection circuit, and recording the amplitude control code, the hysteresis control code and the offset voltage code corresponding to the signal detection indicator in a second look-up table.

Description

BRIEF DESCRIPTION OF THE DRAWINGS

[0013] FIG. 1 illustrates one of various examples of a system for calibrating offsets and thresholds in loss of signal detection circuit.

[0014] FIG. 2 illustrates one of various examples of a variable amplitude signal generator.

[0015] FIG. 3 illustrates one of various examples of a hysteresis comparator with programmable thresholds.

[0016] FIG. 4 illustrates one of various examples of modes of operation without temperature compensation.

[0017] FIG. 5 illustrates another example of modes of operation including temperature compensation.

[0018] FIG. 6 illustrates one of various examples of a method of offset calibration across hysteresis control codes.

[0019] FIG. 7A illustrates one of various examples of a method of calculating hysteresis control values.

[0020] FIG. 7B illustrates one of various examples of signals during a hysteresis calibration.

[0021] FIG. 8 illustrates one of various examples of signals in a loss of signal detection system.

[0022] FIG. 9A illustrates one of various examples of offset calibration and hysteresis calibration

without temperature compensation.

[0023] FIG. 9B illustrates one of various examples of offset calibration and hysteresis calibration with temperature compensation.

DETAILED DESCRIPTION

[0024] FIG. 1 illustrates one of various examples of a system **100** for calibrating offsets and thresholds in a loss of signal (LOS) detection circuit.

[0025] System **100** may include one or more signal inputs. The one or more signal inputs may include a positive polarity input **101** and a negative polarity input **102**. Positive polarity input **101** and negative polarity input **102** may be coupled to analog front end (AFE) **110**.

[0026] Positive polarity input **101** and negative polarity input **102** may be coupled to first switch network **120** and second switch network **130**. First switch select signal **121** may control the configuration of first switch network **120**. Second switch select signal **131** may control the configuration of second switch network **130**. The output of second switch network **130** may be termed a calibration voltage input.

[0027] Reference clock **141** may be input to programmable divider **140**. Programmable divider **140** may generate positive polarity divider output **143** and negative polarity divider output **144** based on reference clock **141** and divider control signal **142**. Divider control signal **142** may specify a divide ratio, and programmable divider **140** may divide reference clock **141** by the specified divide ratio.

[0028] The outputs of first switch network **120** may be coupled to comparator **160**. Comparator **160** may generate comparator output **161**. Comparator output **161** may be input to transition detection circuit **190**. A reset signal **191** may be input to transition detection circuit **190**. Transition detection circuit **190** may output signal detection indicator **199**. Transition detection circuit **190** may detect a change in the value of comparator output **161**.

[0029] Signal detection indicator **199** may be input to threshold calibration circuit **180**. Threshold calibration circuit **180** may output amplitude control signal **152**. Amplitude control signal **152** may be input to amplitude thermometer decoder **155**. The output of amplitude thermometer decoder **155** may be amplitude control code **153**. Amplitude control code **153** may be input to variable amplitude signal generator **150**. Variable amplitude signal generator **150** may generate one or more signal outputs based on positive polarity divider output **143** and negative polarity divider output **144** and based on amplitude control code **153**. Amplitude control code **153** may be input to variable amplitude signal generator **150**. The one or more outputs of variable amplitude signal generator **150** may be input to second switch network **130**.

[0030] Threshold calibration circuit **180** may output hysteresis control signal **181**. Hysteresis control signal **181** may be input to hysteresis thermometer decoder **182**. Hysteresis thermometer decoder **182** may output hysteresis control code **186**. Hysteresis control code **186** may be input to comparator **160** and may set a hysteresis setting in comparator **160**. Comparator **160** may also be termed a transition detection comparator and may also be termed a valid amplitude signal transition detection comparator.

[0031] Comparator output **161** may be input to offset calibration logic circuit **183**, and offset calibration logic circuit **183** may generate an offset control code **184**. Offset control code **184** may be input to digital-to-analog converter (DAC) **165**, which may generate a positive voltage **166** and negative voltage **167** to comparator **160**. Positive voltage **166** may comprise an offset voltage input to comparator **160**. Negative voltage **167** may comprise an offset voltage input to comparator **160**. Positive voltage **166** and negative voltage **167** may comprise a pair of signals in a differential configuration.

[0032] In operation, during an offset calibration mode, a first switch select signal **121** may be set to couple the outputs of second switch network **130** to the inputs of comparator **160**. Voltage Common Mode (VCM) signal **132** may be a common mode voltage of comparator **160**. Second switch select signal **131** may be set to couple the VCM signal **132** to the inputs of first switch network **120**. In this manner, VCM signal **132** may be coupled to the inputs of comparator **160**. In the offset

calibration mode, for respective values of hysteresis control signal **181**, offset control code **184** may be swept from a minimum value to a maximum value or from a maximum value to a minimum value. The value of offset control code **184** corresponding to a change in polarity of comparator output **161** may be stored in a first lookup table as the offset value for respective values of hysteresis control signal **181**.

[0033] In operation, during a hysteresis calibration mode, first switch select signal **121** may be set such that first switch network **120** may couple the outputs of second switch network **130** to the inputs of comparator **160**. Second switch select signal **131** may be set such that second switch network **130** may couple outputs of variable amplitude signal generator **150** to the inputs of first switch network **120**. In the hysteresis calibration mode, for respective values of amplitude control signal **152**, hysteresis control signal **181** may be swept from a minimum value to a maximum value or from a maximum value to a minimum value. At respective settings of hysteresis control signal **181**, offset control code **184** may be set based on the value stored in the first lookup table as described previously. In a second lookup table, values of hysteresis control signal **181** and offset control signal **152** may be recorded corresponding to a change in signal detection indicator **199** for respective amplitude control signal values.

[0034] In one of various examples, comparator output **161** and signal detection indicator **199** may be coupled to controller **189**. Controller **189** may control system **100** and enable the offset calibration mode and the hysteresis calibration mode at predetermined times. Controller **189** may be a microcontroller or may be part of a larger system-on-a-chip. Controller **189** may be a dedicated hardware component for control of system **100**.

[0035] During a normal mode, first switch network **120** may couple positive polarity input **101** and negative polarity input **102** to the inputs of comparator **160**.

[0036] Transition detection circuit **190**, threshold calibration circuit **180**, hysteresis thermometer decoder **182**, offset calibration logic circuit **183**, DAC **165**, programmable divider **140**, variable amplitude signal generator **150**, and amplitude thermometer decoder **155** may comprise a calibration control circuit.

[0037] FIG. 2 illustrates one of various examples of a variable amplitude signal generator **200**. Variable amplitude signal generator **200** may include a positive clock input **201** and a negative clock input **202**. Positive clock input **201** may be coupled to positive polarity divider output **143** as described and illustrated in reference to FIG. 1. Negative polarity input **102** may be coupled to negative polarity divider output **144** as described and illustrated in reference to FIG. 1. Positive clock input **201** may be input to first inverter **210**, and the output of first inverter **210** may be input to second inverter **211**. The output of second inverter **211** may be input to resistor **212**.

[0038] Negative clock input **202** may be input to third inverter **220**, and the output of third inverter **220** may be input to fourth inverter **221**. The output of fourth inverter **221** may be input to resistor **222**.

[0039] Fixed resistor elements **230** may be coupled between resistor **212** and resistor **222**.

Programmable resistor elements **240** may be coupled between resistor **212** and **222**. Fixed resistor elements **230** may be in parallel with programmable resistor elements **240**.

[0040] One or more control signals **250** may modify the resistance of programmable resistor elements **240** and may modify the amplitude of positive output **290** and negative output **291**. In one of various examples, control signal **250** may be coupled to amplitude control code **153** as described and illustrated in reference to FIG. 1.

[0041] FIG. 3 illustrates one of various examples of a hysteresis comparator **300** with programmable hysteresis threshold. Hysteresis comparator **300** may be one of various examples of comparator **160** as described and illustrated in reference to FIG. 1.

[0042] Devices **301** and **302** may modify the amount of hysteresis at positive input **310** and negative input **311**, based on the settings of switch controls **351**, **352**, **361**, **362**. Device **301** may be illustrated as a signal device, but in one of various examples, device **301** may comprise multiple

discrete devices, each with dedicated switch controls. As one of various examples, device **301** may comprise 15 discrete devices. Device **302** may be illustrated as a signal device, but in one of various examples, device **302** may comprise multiple discrete devices, each with dedicated switch controls. As one of various examples, device **302** may comprise 15 discrete devices.

[0043] Switch control **352** may selectively couple the gate of device **301** to first stage comparator output **322**. Switch control **362** may selectively couple the gate of device **302** to first stage comparator output **321**.

[0044] Positive input **310** may be one of various examples of the positive polarity input **126** of comparator **160** as described and illustrated in reference to FIG. 1. Negative input voltage **311** may be one of various examples of the negative polarity input **127** of comparator **160** as described and illustrated in reference to FIG. 1.

[0045] Positive DAC voltage **326** may be one of various examples of positive voltage **166**, an output of DAC **165**, as described and illustrated in reference to FIG. 1. Negative DAC voltage **327** may be one of various examples of negative voltage **167**, an output of DAC **165**, as described and illustrated in reference to FIG. 1.

[0046] In operation, switch control **351** and **352** may selectively enable device **301** and may control the hysteresis threshold of hysteresis comparator **300**. In operation, switch control **361** and **362** may selectively enable device **302** and may control the hysteresis threshold of hysteresis comparator **300**.

[0047] Node **399** may comprise the output of hysteresis comparator **300**. Node **399** may represent comparator output **161**, an output of comparator **160**, as described and illustrated in reference to FIG. 1. Node **399** may transition based on the voltage at positive input **310**, negative voltage **311**, and the hysteresis setting controlled by switch control **351**, **352**, **361** and **362**.

[0048] FIG. 4 illustrates one of various examples of modes of operation in a loss of signal detection system without temperature compensation. Modes of operation may include an offset calibration mode **401**, a hysteresis calibration mode **402** and a normal mode **403**.

[0049] In an offset calibration mode **401**, an offset calibration step may be executed at operation **410**. An offset value may be determined in operation **420**, and an offset calibration value **425** may be input to the loss of signal detection system **490**. Offset calibration value **425** may be written to an amplifier hysteresis lookup table. Offset calibration mode **401** may be performed at a first temperature **T1**.

[0050] In a hysteresis calibration mode **402**, a hysteresis calibration step may be executed at operation **430**. A hysteresis code lookup table may be accessed for each amplitude selection code in operation **430**, based on the output of the hysteresis calibration step at operation **430** and a amplifier select code **461**. A hysteresis control value **445** and respective hysteresis code values related to offset code may be set and may be input to the loss of signal detection system **490**. An amplifier hysteresis lookup table may be accessed, and a hysteresis control value at operation **440** may be set and may be input to the loss of signal detection system. Hysteresis calibration mode **402** may be performed at a first temperature **T1**.

[0051] In a normal mode **403**, an input may be provided at operation **450** which indicates the data rate or the run length of a random data pattern. Based on the input provided, a different amplitude selection control code may be selected for the respective data rate or the run length. Based on the respective selected amplifier select code **461**, the respective calibrated hysteresis code is selected from a lookup table generated in operation **440** and respective offset code for the respective hysteresis code calibrated in operation **420** may be input to loss of signal detection system **490** during normal mode of operation.

[0052] FIG. 5 illustrates an example of modes of operation including temperature compensation. Modes of operation may include an offset calibration mode **501**, a hysteresis calibration mode **502** and a normal mode **503**.

[0053] In an offset calibration mode **501**, an offset calibration step may be executed at operation

510 and an offset value may be determined. In operation **520**, an offset value of the comparator for respective hysteresis control codes of the comparator may be written to lookup table **525**. Lookup table **525** may be input to loss of signal detection system **590**. Offset calibration mode **501** may be performed at a first temperature **T1**.

[0054] In a hysteresis calibration mode **502**, a hysteresis calibration step may be executed at operation **530**. An amplifier hysteresis lookup table may be accessed, and based on the output of the hysteresis calibration step at operation **530** and an amplifier select code **561**, a hysteresis control value **545** may be set. Hysteresis calibration mode **502** may be performed at a first temperature **T1**.

[0055] In a normal mode **503**, an input may be provided at operation **550** which indicates the data rate or run length of a random data pattern. Based on the input provided from operation **550**, an amplitude select code may be selected for the respective data rate or run length and may be used as part of a lookup operation to determine hysteresis control value **545**.

[0056] Normal mode **503** may operate at a different temperature **T2** from the temperature **T1** of the offset calibration mode **501** and the hysteresis calibration mode **502**. A temperature compensation hysteresis offset code calibration may be performed at operation **570**, and may output a calibrated value to hysteresis control at operation **580**. The temperature compensation hysteresis offset code calibration performed at operation **570** may be based on a temperature measurement.

[0057] Based on the output of hysteresis calibration lookup at operation **540** and the temperature compensation hysteresis offset code calibration performed at operation **570**, resultant hysteresis code output at operation **580** may be input to loss of signal detection system **590**.

[0058] FIG. **6** illustrates one of various examples of a method of offset calibration across hysteresis control codes.

[0059] At operation **610**, a calibration enable signal may be enabled and an offset calibration enable signal may be enabled, and an offset calibration routine may be started. A hysteresis control code may be incremented from a minimum value to a maximum value. At operation **620**, the results of the incremental sweep of the offset control code may be input to a DAC, as described and illustrated in reference to DAC **165** of FIG. **1**, and the output of the DAC may be applied to positive voltage **166** and negative voltage **167** as described and illustrated in reference to FIG. **1**.

[0060] At operation **633**, a positive sweep may be initiated and may modify the output of the DAC from a minimum value to a maximum value. The positive sweep may set a maximum positive offset at operation **643** if no low-to-high transition is detected at comparator output **161** during the sweep, and may set a maximum negative offset at operation **644** if the comparator output **161** is high at the maximum negative offset.

[0061] At operation **632**, a negative sweep may be initiated and may modify the DAC output from a maximum value to a minimum value. The negative sweep may set a maximum positive offset at operation **642** if the comparator output **161** is low at the maximum value and may set a maximum negative offset at operation **641** if no high-to-low transition is detected at comparator output **161** during the sweep.

[0062] When a comparator detects a high-to-low transition, operation **631** may set a falling edge negative offset at the current offset value. When a comparator detects a low-to-high transition, operation **634** may set a rising edge positive offset at the current offset value. Operation **650** may calculate an average of the input offset values from operations **631**, **641**, **642**, **644**, **643** and **634**. Operation **660** may save the average values to a lookup table.

[0063] FIG. **7A** illustrates one of various examples of a method of calculating hysteresis control values.

[0064] At operation **710**, a calibration enable signal and an offset calibration enable signal may be deasserted and this state may enable a hysteresis calibration mode.

[0065] An offset code **184** may be computed based on an offset calibration as described and illustrated in reference to FIG. **1**. A hysteresis control code **186**, as described and illustrated in

reference to FIG. 1, may be set to a maximum value.

[0066] At operation **720**, the amplitude control code input to the variable amplitude signal generator may be swept from a maximum value to a minimum value. The amplitude control code may be an amplitude control code **153** as described and illustrated in reference to FIG. 1.

[0067] At operation **730**, the output of the transition detection comparator may be monitored. The transition detection comparator may be one of various examples of transition detection circuit **190** as described and illustrated in reference to FIG. 1. When a transition is detected, operation **740** may record values of the hysteresis control code and the amplitude control code at the transition point. Operation **750** may save the recorded values of the hysteresis control code and the amplitude control code to a lookup table.

[0068] If a transition is not detected in the transition detection comparator at operation **730**, operation **731** may decrease the value of the hysteresis control code and return to operation **730**. The transition detection comparator may be one of various examples of transition detection circuit **190** as described and illustrated in reference to FIG. 1. If the hysteresis control code is decrease and is set to zero at operation **731**, operation **732** may set the hysteresis control code to the previous calibration value and return to operation **720**.

[0069] FIG. 7B illustrates one of various examples of signals during a hysteresis calibration.

[0070] Trace **761** may represent a reset signal input to programmable divider **140** as described and illustrated in reference to FIG. 1. Trace **761** may be an active low reset signal as illustrated in FIG. 7B, or may be an active high reset signal. Trace **761** may allow time for signals to settle prior to the next active phase of hysteresis calibration.

[0071] Trace **762** may represent a reset signal input to transition detection circuit **190**. Trace **762** may represent a clear signal or a refresh signal.

[0072] Trace **763** may represent an output of programmable divider **140** as described and illustrated in reference to FIG. 1. Trace **763** may toggle in response to trace **761** transitioning from an logic low reset state to a logic high active state.

[0073] Trace **764** may represent an input signal to transition detection circuit **190**. In one of various examples, trace **764** may represent a differential voltage at the input of comparator **160**, represented by the difference between positive polarity input **126** and negative polarity input **127**, as described and illustrated in reference to FIG. 1.

[0074] Trace **765** may represent an input to signal to transition detection circuit **190**. In one of various examples, trace **765** may represent a voltage on comparator output **161** as described and illustrated in reference to FIG. 1.

[0075] Trace **766** may represent an output of transition detection circuit **190**.

[0076] In operation, a voltage on trace **766** may control threshold calibration circuit **180** which may modify hysteresis control signal **181** and amplitude control signal **152** as part of a hysteresis calibration mode.

[0077] FIG. 8 illustrates one of various examples of signals in a loss of signal detection system.

[0078] Trace **810** may represent a hysteresis control code. The hysteresis control code may remain constant during the time represented in FIG. 8.

[0079] Trace **820** may represent a clear/refresh signal for transition detection. The clear/refresh signal may be one of various examples of reset signal **191** as described and illustrated in reference to FIG. 1. Trace **820** represents an active-low clear/refresh signal, but this is not intended to be limiting.

[0080] Trace **830** may represent a difference between a positive input and a negative input to a comparator. In one of various examples, trace **830** may represent the difference between positive input **310** and negative input **311** as described and illustrated in reference to FIG. 3. Trace **840** may represent a difference between internal nodes of the comparator. In one of various examples, trace **840** may represent the difference between first stage comparator outputs **321** and **322** as described and illustrated in reference to FIG. 3.

[0081] Trace **850** may represent comparator output **161** as described and illustrated in reference to FIG. **1**. Trace **850** may be asserted based on trace **830** exceeding a predetermined threshold. Trace **860** may represent a transition detection signal. Trace **860** may represent a transition detection circuit output signal **199** as described and illustrated in reference to FIG. **1**. The transition detection signal represented by trace **860** may assert based on a transition in trace **850**, as represented at locations **851**, **852** and **853**. Trace **860** may be reset based on the clear/refresh signal of trace **820** reaching a logic low level, as shown at locations **825** and **826**. The assertion of trace **860** at locations **852** and **853** may occur due to transitions of trace **850**. Trace **850** may be monitored by transition detection circuit **190** and may result in changes to transition detection signal **199**.

Transition detection signal **199** may be a transition detection indicator.

[0082] FIG. **9A** illustrates one of various examples of offset and hysteresis calibration without temperature compensation. FIG. **9A** illustrates another example of offset and hysteresis calibration as described and illustrated in reference to FIG. **4**.

[0083] At operation **910**, an offset calibration may be performed, during which an offset DAC code and direction may be swept for each hysteresis control code setting. An offset value may be output to loss of signal detection system **935**. At operation **920**, a hysteresis calibration may be performed, during which for each amplitude control code, the hysteresis control code may be swept from a minimum value to a maximum value. At each setting of the amplitude selection control code, and a hysteresis value may be output to loss of signal detection system **935**.

[0084] At operation **941**, offset values may be written to lookup table **940** for each hysteresis control code. At operation **946**, an offset value and a hysteresis control code may be written to lookup table **945** for values of the amplitude control code. Transition detection signal **948** may be output from loss of signal detection system **935**.

[0085] Lookup table **930** may be used to select values of the amplitude control code, the hysteresis control code and the offset value based on an input, the input to specify one of a data rate and a run length.

[0086] FIG. **9B** illustrates one of various examples of offset and hysteresis calibration with temperature compensation. FIG. **9B** illustrates another example of offset and hysteresis calibration as described and illustrated in reference to FIG. **5**.

[0087] At operation **960**, an offset calibration may be performed and an offset value may be output to loss of signal detection system **986**. At operation **970**, a hysteresis calibration may be performed, and a hysteresis value may be output to loss of signal detection system **986**.

[0088] At operation **991**, offset values may be written to lookup table **940** for each hysteresis control code. At operation **996**, an offset value and a hysteresis control code may be written to lookup table **995** for values of the amplitude control code. Transition detection signal **989** may be output from loss of signal detection system **986**. Lookup table **999** may be used to modify the hysteresis control code based on measured temperature.

[0089] At operation **980**, a look up table may be used to select values of amplitude control code, hysteresis control code and offset. At operation **985**, a temperature compensation may be performed and may modify the hysteresis control code.

Claims

1. A system comprising: one or more signal inputs coupled to a first switch network and coupled to an analog front end (AFE) circuit; a comparator with one or more comparator inputs, a hysteresis control code input and at least one offset voltage input, the first switch network to selectively couple one of the one or more signal inputs and one or more calibration voltage inputs to the one or more comparator inputs, the comparator coupled to a calibration control circuit; a transition detection circuit coupled to one or more outputs of the comparator, the transition detection circuit to generate a signal detection indicator; the calibration control circuit comprising: a programmable

divider to divide a reference clock; a variable amplitude signal generator to receive the output of the programmable divider and an amplitude control code, the variable amplitude signal generator to generate a signal with an amplitude based on the amplitude control code; a second switch network to receive input from the output of the variable amplitude signal generator and from a common mode voltage, the second switch network to couple the common mode voltage to the calibration voltage inputs in an offset calibration mode and the second switch network to couple the outputs of the variable amplitude signal generator to the calibration voltage inputs in a hysteresis calibration mode; a threshold calibration circuit to take input from the signal detection indicator and to generate a hysteresis control signal, the hysteresis control signal coupled to the hysteresis control code input of the comparator and the threshold calibration circuit to generate an amplitude control signal, the amplitude control signal coupled to the variable amplitude signal generator; an offset calibration logic circuit to take input from the one or more outputs of the comparator and to generate the at least one offset voltage input to the comparator, and a controller to receive input from the comparator output and the signal detection indicator and to enable the offset calibration mode and the hysteresis calibration mode based on the comparator output and the signal detection indicator.

2. The system as claimed in claim 1, the at least one offset voltage input comprising two voltage inputs in a differential configuration.

3. The system as claimed in claim 1, the programmable divider comprising a divider control signal to specify a divide ratio.

4. The system as claimed in claim 1, the offset calibration logic circuit comprising a logic circuit to take input from the one or more comparator outputs and a digital-to-analog converter (DAC) to convert the output of the logic circuit to one or more analog voltages, the one or more analog voltages coupled to the at least one offset voltage input of the comparator.

5. The system as claimed in claim 1, the controller to enable the offset calibration mode for a first predetermined time and to enable the hysteresis calibration mode for a second predetermined time, the first predetermined time to begin and end prior to the beginning of the second predetermined time.

6. The system as claimed in claim 1, the controller to control the first switch network to couple the one or more calibration voltage inputs to the comparator inputs during the offset calibration mode and during the hysteresis calibration mode.

7. The system as claimed in claim 1, the controller to populate a first look-up table based on a transition in the comparator output.

8. The system as claimed in claim 7, the first look-up table comprising hysteresis control codes and offset control codes.

9. The system as claimed in claim 1, the controller to populate a second look-up table based on a transition in the signal detection indicator.

10. The system as claimed in claim 9, the second look-up table comprising hysteresis control codes, amplitude control codes, and offset control codes.

11. The system as claimed in claim 1, the AFE circuit, comparator, transition detection circuit, calibration control circuit and controller part of a microcontroller.

12. A method comprising: performing an offset calibration of a comparator, the offset calibration comprising: coupling one or more inputs of a comparator to a common mode voltage; setting a hysteresis control code; coupling the hysteresis control code to a hysteresis setting input of the comparator; sweeping an offset control code to the comparator in one or more steps from a first value to a second value; detecting a change in polarity of the comparator output; recording a value of the offset control code corresponding to the change in polarity of the comparator output for respective values of the hysteresis control code; repeating the offset calibration for respective values of the hysteresis control code to generate a first look-up table of offset control codes and respective hysteresis control codes; performing a hysteresis calibration of the comparator, the

hysteresis calibration comprising: setting an amplitude control code and a hysteresis control code; coupling the amplitude control code to an input of a variable amplitude signal generator and coupling the hysteresis control code to the comparator; sweeping the hysteresis control code in one or more steps from a maximum value to a minimum value and setting the offset voltage input to the comparator at respective steps based on values recorded in the first look-up table; detecting a signal detection indicator of a transition detection circuit, and recording the amplitude control code, the hysteresis control code and the offset control code corresponding to the signal detection indicator in a second look-up table.

13. The method as claimed in claim 12, comprising compensating the hysteresis control code based on a temperature measurement and at least one of the first look-up table and the second look-up table.

14. The method as claimed in claim 12, the first value of the offset voltage input comprising a maximum value and the second value of the offset voltage input comprising a minimum value.

15. The method as claimed in claim 12, the first value of the offset voltage input comprising a minimum value and the second value of the offset voltage input comprising a maximum value.
